

An American National Standard

IEEE Guide for Aging Mechanisms and Diagnostic Procedures in Evaluating Electrical Insulation Systems

Sponsor

IEEE Standards Coordinating Committee 4, Thermal Rating

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IEEE Standards Board

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Foreword

(This Foreword is not a part of ANSI/IEEE Std 943-1986, IEEE Guide for Aging Mechanisms and Diagnostic Procedures in Evaluating Electrical Insulation Systems.)

This guide was developed to aid equipment committees standardize tests for use in evaluating electrical insulation systems. In the development of this guide the IEC Publication 610 (1978), Principal Aspects of Functional Evaluation of Electrical Insulation Systems: Aging Mechanisms and Diagnostic Procedures, was followed closely. When this guide was approved the IEEE Standards Coordinating Committee 4, Thermal Rating had the following membership:

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